Key Points addressed in this Topic



Memory & Memory Interface

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Taxonomy of Memories

- Memory organisation
- Static memory timing
- Embedded RAM in Virtex FPGA dual port RAM
- SRAM application FIFO
- Dynamic memory
- Synchronous DRAM (SDRAM)
- SDRAM Timing

Slides based on notes from Paolo Ienne, EPFL & David Cullen, Berkeley.

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Taxonomy of Memories Associative **Implicit Addressing** Random Access CAM Single Port Multiport Serial **FIFO** LIFO **Special Purpose** ROM RAM **Register File** PYKC 3-Mar-08 Topic 8 Slide 3 E3.05 Digital System Design

Taxonomy of Random Access Memory



Register File





Register File Internals



Accessing Register Files

- Read: output is a combinational function of the address input
- Write is synchronous
 - If enabled, input data is written to selected word on the clock edge
- Often multi-ported



Simplified RAM organization



Different internal array organization



Typical organisation for a 4K x 16 bit RAM



Typical SRAM Timing



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Memory Blocks in FPGAs

- LUTs can double as small RAM blocks:
- Newer FPGA families include larger on-chip RAM blocks (usually dual ported):
 - Called block selectRAMs in Xilinx Virtex series
 - 4k bits each



Virtex "Block RAMs"

- Each block SelectRAM (block RAM) is a fully synchronous (synchronous write and read) dual-ported (true dual port) 4096bit RAM with independent control signals for each port. The data widths of the two ports can be configured independently, providing built-in buswidth conversion.
- CLKA and CLKB can be independent, providing an easy way to "cross clock boundaries".
- Around 160 of these on the XCV2000E. Multiples can be combined to implement, wider or deeper memories.



Synchronous SRAM timing



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Dual-ported Memory Internals



First-in-first-out (FIFO) Memory

- Used to implement queues.
- These find common use in computers and communication circuits.
- Generally, used for rate matching data producer and consumer:



- Producer can perform many writes without consumer performing any reads (or vice versa). However, because of finite buffer size, on average, need equal number of reads and writes.
- Typical uses:
 - interfacing I/O devices. Example network interface. Data bursts from network, then processor bursts to memory buffer (or reads one word at a time from interface). Operations not synchronized.
 - Example: Audio output. Processor produces output samples in bursts (during process swap-in time). Audio DAC clocks it out at constant sample rate.

FIFO Interfaces



FIFO Implementation

- Assume, dual-port memory with asynchronous read, synchronous write.
- Binary counter for each of read and write address. CEs controlled by WE and RE.
- Equal comparator to see when pointers match.
- Flip-flop each for FULL and EMPTY flags:

WE RE	equal	EMPTY _i	FULL _i
0 0	0	0	0
0 0	1	EMPTY _{i-1}	FULL _{i-1}
0 1	0	0	0
0 1	1	1	0
10	0	0	0
10	1	0	1
11	0	0	0
11	1	EMPTY _{i-1}	FULL _{i-1}

SRAM vs DRAM



- ☆ Capacitor discharges (leakage) and needs refresh every some time ("seldom", i.e. typ. ~10ms)
- # Additional design complexity (sometimes hidden from the designer, esp. in ASIC)

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Classical DRAM Organization (Square)



DRAM Logical Organization (4 Mbit)



Logic Diagram of a Typical DRAM



- Control Signals (RAS_L, CAS_L, WE_L, OE_L) are all active low
- Din and Dout are combined (D):
 - WE_L is asserted (Low), OE_L is disasserted (High)
 D serves as the data input pin
 - WE_L is disasserted (High), OE_L is asserted (Low)
 D is the data output pin
- Row and column addresses share the same pins (A)
 - RAS_L goes low: Pins A are latched in as row address
 - CAS_L goes low: Pins A are latched in as column address
 - RAS/CAS edge-sensitive



Basic DRAM read & write

DRAM READ Timing



DRAM WRITE Timing



Key DRAM Timing Parameters

- t_{RAC}: minimum time from RAS line falling to the valid data output.
 - Quoted as the speed of a DRAM
 - A fast 4Mb DRAM $t_{RAC} = 60 \text{ ns}$
- t_{RC}: minimum time from the start of one row access to the start of the next.
 - + $t_{\text{RC}}\,$ = 110 ns for a 4Mbit DRAM with a t_{RAC} of 60 ns
- t_{CAC}: minimum time from CAS line falling to valid data output.
 - 15 ns for a 4Mbit DRAM with a $t_{\mbox{\tiny RAC}}$ of 60 ns
- t_{PC}: minimum time from the start of one column access to the start of the next.
 - 35 ns for a 4Mbit DRAM with a $t_{\mbox{\tiny RAC}}$ of 60 ns

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Memory in Desktop Computer Systems:

- SRAM (lower density, higher speed) used in CPU register file, on- and offchip caches.
- DRAM (higher density, lower speed) used in main memory





Closing the GAP:

- 1. Caches are growing in size.
- Innovation targeted towards higher bandwidth for memory systems:
 - SDRAM synchronous DRAM
 - RDRAM Rambus DRAM
 - EDORAM extended data out SRAM
 - Three-dimensional RAM
 - hyper-page mode DRAM video RAM
 - multibank DRAM

DRAM with Column buffer



Optimized Access to Cols in Row

READ burst (with auto precharge)



WRITE burst (with auto precharge)



Simplified DRAM timing (burst mode)



Simplified SDRAM Timing (burst mode)



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Error Detection in Memory

- Add extra data bit to ensure total number of 1's is EVEN even parity
- Parity bit is the exclusive-OR of all other data bits
- If one of the received bit is wrong, then number of 1's will be odd (including parity bit) and error is detected

Data	Parity bit	number of 1's
1101110	1	6
0101101	0	4



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• If D2 is in error, check bits P1 & P2 will be wrong:

Example



Error Correction in Memory

- Simply parity is limiting in its ability to detect error
- It cannot CORRECT error
- Use multiple check bits, each giving parity for a DIFFERENT COMBINATION of data bits
- If a data bit is wrong, it will affect only some check bits from which deduce WHICH bit is wrong:

	DO	D1	D2	D3	
PO:	x	x		x	PO ≃ DO ⊕ D1 ⊕ D3
P1:	x		x	x	P1 = D0 🖶 D2 🕞 D3
F2:		x	x	x	P2 = D1 ⊕ D2 ⊕ D3
Code:	3	5	6	7	(0,1,2,4 not used)
 Each dat 	a bit affe	cts a UNI	IQUE con	nbination o	of check bits

 Each data bit affects at least TWO check bits – this means an error in check bit is not confused with error in data bit

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More on check bits

- N check bits are sufficient for 2^N N 1 data bits
 - Each data bit must affect a different combination of check bits
 - There are 2^N possible combinations for N check bits
 - Of these, N affect only 1 bit and 1 affects no bits at all
- If you regard the combinations as binary numbers, then for 3 check bits, numbers 0, 1, 2 and 4 are ruled out, leaving 3, 5, 6, 7 as useful:

	DO	D1	D2	D3	
PO:	x	x		x	PO = DO 🕀 D1 🔁 D3
P1:	x		x	x	P1 = D0 🔁 D2 🕞 D3
F2:		x	x	x	P2 ≃ D1 ⊕ D2 ⊕ D3
Code:	3	5	6	7	(0,1,2,4 not used)

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ECC for 8 bit bytes

- Detect and correct any single bit error
- Can add an extra check bit giving overall parity to both data & check bits
 - will detect double bit errors but not correct
 - For double errors, overall parity bit will be OK, but check bits is wrong

	DO	D1	D2	D3	D4	D5	D6	D7	
PO:	x	x		x	x		x		
P1:	x		x	x		x	x		
P2:		x	x	x				x	
P3:					x	x	x	x	
Code:	3	5	6	7	9	10	11	12	(0,1,2,4,8 not used, 13,14,15 spare)

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Error detection in block of data

- Method 1: Add up all data words, ignore carry(s) and store result as CHECKSUM
 - Advantages: Very easy to do
 - Disadvantages: Errors can cancel out; will not detect gross errors such as MSB stuck at '0'
- Method 2: Form checksum as before, but add an extra 1 each time you get a carry.
 - Equivalent to doing addition modulo 2ⁿ-1 instead of module 2ⁿ, where n is the number of bits in each data word
 - Advantages: Almost as easy as before; less likely to ignore gross errors
 - Disadvantages: Errors can still cancel e.g. a '1' changes to '0' and later a '0' changes to '1' in the same bit

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Error detection in block of data - CRC

- Method 3: Cyclic Redundancy Check (CRC)
 - Send data through a shift register incorporating a feedback loop
 - Implement 'polynomial division' check because the action of the shift register is mathematically equivalent to dividing one algebraic polynomial by another polynomial.
 - Shown here is one using polynomial $x^{16}+x^{12}+x^5+1$: used by floppy disks
 - Whatever is left in shift register after all data bits are received is used a checksum



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Primitive Polynomial Table

Degree (n)	Polynomial	Degree (n)	Polynomial
2, 3, 4, 6, 7, 15, 22, 60, 63	$x^{n} + x + 1$	12	$x^{n} + x^{7} + x^{4} + x^{3} + 1$
5, 11, 21, 29, 35	$x^{n} + x^{2} + 1$	33	$x^n + x^{13} + 1$
8, 19, 38, 43	$x^{n} + x^{6} + x^{5} + x + 1$	34	$x^{n} + x^{15} + x^{14} + x + 1$
9, 39	$x^{n} + x^{4} + 1$	36	$x^{n} + x^{11} + 1$
10, 17, 20, 25, 28, 31, 41, 52	$x^{n} + x^{3} + 1$	37	$x^{n} + x^{12} + x^{10} + x^{2} + 1$
13, 24, 45, 64	$x^{n} + x^{4} + x^{3} + x + 1$	40	$x^{n} + x^{21} + x^{19} + x^{2} + 1$
14, 16	$x^{n} + x^{5} + x^{4} + x^{3} + 1$	42	$x^{n} + x^{23} + x^{22} + x + 1$
18, 57	$x^{n} + x^{7} + 1$	46	$x^{n} + x^{21} + x^{20} + x + 1$
23, 47	$x^{n} + x^{5} + 1$	54	$x^{n} + x^{37} + x^{36} + x + 1$
26, 27	$x^{n} + x^{12} + x^{11} + x + 1$	55	$x^{n} + x^{24} + 1$
30, 51, 53, 61, 70	$x^n + x^{16} + x^{15} + x + 1$	58	$x^{n} + x^{19} + 1$
32, 48	$x^{n} + x^{28} + x^{27} + x + 1$	65	$x^{n} + x^{18} + 1$
44, 50	$x^{n} + x^{27} + x^{26} + x + 1$	69	$x^{n} + x^{29} + x^{27} + x^{2} + 1$
49, 68	$x^{n} + x^{9} + 1$	71	$x^{n} + x^{6} + 1$
56, 59	$x^{n} + x^{22} + x^{21} + x + 1$	72	$x^{n} + x^{53} + x^{47} + x^{6} + 1$
66, 67, 74	$x^{n} + x^{10} + x^{9} + x + 1$	73	$x^{n} + x^{25} + 1$

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